

XAFS Mass

1. Calculation of mass and absorption step for powder samples

+?- XAFS mass _ □ X
Powder
$\mathbf{v} = [\boldsymbol{\mu}_{T} \mathbf{d}] \cdot \mathbf{S} \cdot [\boldsymbol{\sum}_i N_{A} N_i 2 r_{o} \mathcal{A} \boldsymbol{f}_i^{u}]^{-1}; \mathbf{m} = \mathbf{M} \cdot \mathbf{v}$
compound (example: Nd_2Cu0_4 or Fe%5Si0_2):
Cu%4SiO_2
M (g/mol)=62.5883
$\mu_{T}d = 2.6$ S(cm ²) = 0.72
E(eV)= 8979
data table: Henke Plot f"
v(mol) = 8.53016e-4 m(mg) = 53.389
absorptance step= Cu(m=2.136): 0.734
ρ(g/cm ³) = d(μm) =
Calculate About Help

A typical application is the calculation of the mass for a powder sample. The optimal optical sample thickness μd depends on the absorption levels selected for the ionization chambers (see below). Typically, μd is between 2 and 3 (e.g. for a 17.5% absorption level for the 1st chamber and a 50% level for the 2nd chamber, the optimal thickness is 2.41). However, if you get the absorption step more that 1.5, it is recommended to reduce the sample mass to avoid potential thickness effect due to possible inhomogeneity in the wafer. If your sample is diluted and you get a very low absorption step, do not try to make the wafer thicker hoping that you will get better spectra - you will not: The optimal thickness gets the best signal-tonoise ratio (it is in this sense it is optimal). You can only try to measure your absorption spectra with another registration technique: in fluorescence or electron yield modes.

2. Calculation of thickness and absorption step for samples with known density

•?• XAFS mass
Foil, Film, Glas etc.
$d = (\mu_T d) M (\varrho \sum_i N_{ij} N_i 2 r_0 A_{ij}^n)^{-1}$
compound (example: Ag%25Ge_0.4Se_0.6):
Cu
M (g/mol)=63.5460
μ _T d = 2.6
$p(g/cm^3) = 8.96$
E(eV)= 8979
data table: Henke Plot f"
d(µm) = 10.212
absorptance step= Cu: 2.266
Calculate About Help

Here you can calculate the thickness of the sample with known density (usually, a foil). Commercial foils are highly homogeneous in thickness, so that you may ignore large step jumps and pay attention to the total µd only.



*** XAFS mass Gas	
$p = -\ln(1 - obs.level) kT (d: \sum_{i} N_i 2r_o Af_i^{"})^{-1}$ compound (example: Ar_0.1Kr_0.9): Ar M (g/mol)=39.9480 absorption level = 1 - exp(-\mu_Td) = 0.22	For nitrogen, do not forget the 2: N_2 , not just N. Start with the 2nd ionization chamber (IC). If a reference foil is placed between the 2nd and the 3rd IC, the fraction of x-rays absorbed by the 2nd IC is usually set to 50%. If the reference foil is not needed, one can select
d(cm) = 10 E(eV)= 9500	total absorption (100%). For these two cases the optimal absorption of the 1st IC at a certain μ d is found from the following figures showing the levels of signal-to-noise ratio:
p(mbar) = 203.391 Calculate About Help	A A A A A A A A A A A A A A

3. Calculation of gas pressure for ionization chambers

Fraction of x-rays absorbed by I₀ detector 4. Calculation of an unknown elemental concentration

*?• XAFS mass		
Determination of unknown concentration		
compound (example: Cu%xSiD_2):		
Cu%xSiO_2		
M (g/mol)=62.2094		
μ _T d = 1.194		
Δµd = 0.301		
õμd = 0.08		
E(eV)= 8979		
data table: Henke Plot f"		
N _x = 0.03343 wt% _x = 3.4153±0.1711		
Calculate About Help		

Case 1: You know the composition of the matrix. You need an absorption spectrum taken without the sample (empty spectrum) but with the same state of the ionization chambers. You then subtract it from the spectrum of the sample (e.g. in <u>VIPER</u>) and get a real (i.e. not shifted vertically) absorption coefficient. Determine the value of µd above the edge ($\mu_T d$), the edge jump ($\Delta \mu d$) and its uncertainty ($\delta \mu d$). Specify the chemical formula with x.

Fraction of x-rays absorbed by I_0 detector



*?• XAFS mass
Powder
$\mathbf{v} = (\boldsymbol{\mu}_{T} \mathbf{d}) \cdot S \cdot (\sum_{i} N_{A} N_{i} 2 r_{o} A f_{i}^{n})^{-1}; \mathbf{m} = M \cdot \mathbf{v}$
compound (example: Nd_2Cu0_4 or Fe%5Si0_2):
Cu
M (g/mol)=63.5460
$\mu_{T}d = 0.345$ S(cm ²) = 0.72
E(eV)= 8979
data table: Henke 🗾 Plot f"
v(mol) = 1.37562e-5 m(mg) = 0.874
absorptance step= Cu(m=0.874): 0.301 💽
ρ(g/cm ³) = d(μm) =
Calculate About Help

Case 2: You know the sample mass and area. Determine the edge jump ($\Delta\mu d$). For the pure element find such a value for $\mu_T d$ that the absorption step in the pull-down list was equal to your experimental $\Delta\mu d$. This will give you the mass of the element of interest. Just divide it by the total mass to get the weight percentage.

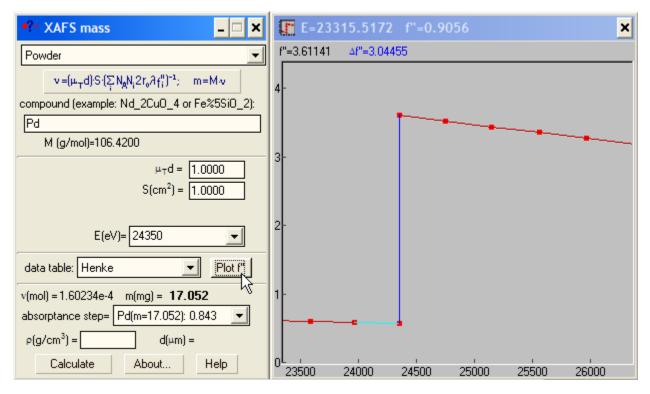
5. Calculation of two unknown elemental concentrations

•?• XAFS mass			
Determination of two unknown concentrations			
$(\Delta \mu/\mu_{T})_{X} = N_{X} \Delta f_{X}^{u} (\sum_{j \neq X \neq g} N_{j} f_{j}^{u} + N_{X} f_{X}^{u} + N_{g} f_{g}^{u})^{-1}$			
compound (example: Cu%xZn%ySiO_2):			
Cu%xZn%ySiO_2			
M (g/mol)=65.1980			
for x: $\mu_T d =$ 2.499 for y: $\mu_T d =$ 2.290 $\Delta \mu d =$ 0.915 $\Delta \mu d =$ 0.256 $\delta \mu d =$ 0.1 $\delta \mu d =$ 0.04			
E(eV)= 8979 E(eV)= 9659			
data table: Henke Plot f"			
$N_x = 0.06152$ wt $x_x = 5.9959 \pm 0.1783$ $N_y = 0.01842$			
wt% _y = 1.8466±0.0549			
Calculate About Help			

Here you also need empty spectra (for each of the two edges) to find the unshifted values for absorption coefficient above both edges.



6. Finding the scattering factors f"



If you need to know the scattering factor f' at different energies and/or its jump at an edge (Δ f''), XAFSmass provides a graphical tool for this.

For example, you may need these values to determine the composition of a binary compound if you have the experimental edge heights at two edges. The absorption step $\Delta\mu d$ at the absorption edge of energy E is proportional to $\Delta f''v/E$, where v is the amount of (resonantly) absorbing atoms in mole. Hence, the atomic ratio of two elements in the same sample is $v_A/v_B = (\Delta\mu d)_A/(\Delta\mu d)_B \cdot [\Delta f''_A/\Delta f''_B \cdot E_A/E_B]$. For binary compounds A_xB_{1-x} the concentration x is calculated then as $x = (v_A/v_B)/[1+(v_A/v_B)]$.